As members of the Open Architecture Initiative, we at GuideTech are excited about this great opportunity to provide our specialized family of products for critical timing test in production.

Timing tests have grown increasingly critical in production due to decreasing geometries and increasing frequencies. Thanks to the initiative of the Semiconductor Test Consortium (STC), we are now able to provide cost effective alternatives with high performance and unprecedented throughput as a fully integrated solution for the Open Architecture.

Based on the STC specifications, the OPENSTART™ platform represents new opportunities for instrument providers such as GuideTech for the seamless integration of third party modules.

Instruments offered:

GuideTech provides Timing Interval Analyzer (TIA) modules that integrate into the test head, bringing the front end of the instrument closest to the DUT for improved signal integrity.

Typical measurements include all timing related tests including frequency, period, rise/fall time, duty cycle, and skew.

Enhanced features allow for Functional Test of Non Deterministic signals at Speed, without the need for an external marker for SerDes and asynchronous buses.

Other tools include DataCom Analysys (DCA) for separation of Jitter components, Eye opening, BER, and many more.

About GuideTech:

Founded in 1988, GuideTech is the leader in precision timing instruments. The US NIST depends on our products to track the accuracy and drift of their atomic clocks, making GuideTech the world time standard. Based upon patented Continuous Time Interval Analyzer technology (CTIA), GuideTech provides test solutions from device characterization for jitter and timing sensitive signals, to critical timing test in production.

The GuideTech Femto family of products enhances the performance of any ATE platform, providing the highest throughput by combining fast measurement rates with multiple measurement channels in parallel.